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Session A: 5G, internet of things (IoT), and over the air (OTA) measurement & calibration

Session Chair: Rusty Myers

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¹IMS Laboratory University of Bordeaux, ²ST Microelectronics

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Roland G Clarke¹, Xiaobang Shang², Nick Ridler², Roger Lozar³, Thorsten Probst⁴, Uwe Arz⁴

¹University of Leeds, ²National Physical Laboratory, ³Fraunhofer IAF, ⁴Physikalisch-Technische Bundesanstalt (PTB)

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¹Modelithics Inc., ²University of South Florida

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